



Jon Madsen has been with KLA for over 16 years and manages the KLA metrology product portfolio including Overlay, Films, Optical CD, CD-SAXS, SensArray (in-situ metrology), MRAM metrology, and Resistivity and Implant metrology. Jon has held a variety of leadership positions in general management, technology development, engineering, program management and semiconductor process development. Jon earned his Master's degree in chemical engineering and Bachelor's degree in Chemistry from the University of Illinois.